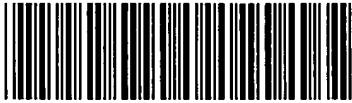


Search Notes

Application/Control No.

10/052,256

Examiner

Chau Nguyen

Applicant(s)/Patent under
Reexamination

TERUUCHI ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	513	8/31/2006	CN
715	514	8/31/2006	CN
715	531	8/31/2006	CN
713	176	8/31/2006	CN
713	179	8/31/2006	CN
713	180	8/31/2006	CN
713	189	8/31/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	12/15/2004	CN
	12/16/2004	CN
	12/17/2004	CN
Updated Search on East Reports	8/23/2005	CN
Updated Search on East Reports	02/07/2006	CN
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	02/09/2006	CN
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Search Notes (continued)

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	DATE	EXMR
Updated Search on East Reports	8/31/2006	CN